EcoSPARK® 2 Ignition IGBT

300 mJ, 400 V, N-Channel Ignition IGBT

Features

- SCIS Energy = 300 mJ at $T_J = 25$ °C
- Logic Level Gate Drive
- AEC-Q101 Qualified and PPAP Capable
- RoHS Compliant

Applications

- Automotive Ignition Coil Driver Circuits
- Coil on Plug Application

MAXIMUM RATINGS (T_J = 25°C unless otherwise stated)

Symbol	Parameter	Value	Units
BV _{CER}	Collector to Emitter Breakdown Voltage (I _C = 1 mA)	400	V
BV _{ECS}	Emitter to Collector Voltage – Reverse Battery Condition (I _C = 10 mA)	28	V
E _{SCIS25}	Self Clamping Inductive Switching Energy (Note 1)	300	mJ
E _{SCIS150}	Self Clamping Inductive Switching Energy (Note 2)	170	mJ
I _{C25}	Collector Current Continuous at VGE = 5.0 V, T _C = 25°C	41	Α
I _{C110}	Collector Current Continuous at VGE = 5.0 V, T _C = 110°C	25.6	Α
V_{GEM}	Gate to Emitter Voltage Continuous	±10	V
P _D	Power Dissipation Total, T _C = 25°C	150	W
	Power Dissipation Derating, T _C > 25°C	1	W/°C
TJ	Operating Junction and Storage Temperature	-55 to 175	°C
T _{STG}	Storage Junction Temperature Range	-55 to 175	°C
T _L	Max. Lead Temperature for Soldering (Package Body for 10 s)	300	°C
T _{PKG}	Max. Lead Temperature for Soldering (Package Body for 10 s)	260	°C
ESD	HBM – Electrostatic Discharge Voltage at 100 pF, 1500 Ω	4	kV
	CDM – Electrostatic Discharge Voltage at 1 Ω	2	kV

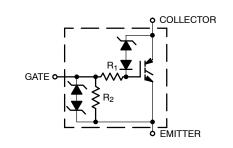
Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

- Self clamped inductive Switching Energy (ESCIS25) of 300 mJ is based on the test conditions that is starting T_J = 25°C, L = 3 mHy, ISCIS = 14.2 A, VCC = 100 V during inductor charging and VCC = 0 V during time in clamp.
- Self Clamped inductive Switching Energy (ESCIS150) of 170 mJ is based on the test conditions that is starting T_J = 150°C, L = 3mHy, ISCIS = 10.8 A, VCC = 100 V during inductor charging and VCC = 0 V during time in clamp.



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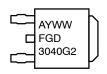
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DPAK (SINGLE GAUGE) CASE 369C

MARKING DIAGRAM



A = Assembly Location

′ = Yeaı

WW = Work Week FGD3040G2= Device Code

ORDERING INFORMATION

See detailed ordering and shipping information on page 2 of this data sheet.

THERMAL RESISTANCE RATINGS

Characteristic		Max	Units
Junction-to-Case - Steady State (Drain)		1	°C/W

ELECTRICAL CHARACTERISTICS (T_J = 25°C unless otherwise specified)

Symbol	Parameter	Test Conditions		Min	Тур.	Max.	Units
FF CHARA	ACTERISTICS						
BV _{CER}	Collector to Emitter Breakdown Voltage	$I_{CE} = 2 \text{ mA}, V_{GE}$ $R_{GE} = 1 \text{ k}\Omega, T_{J}$	= = 0 V, = -40 to 150°C	370	400	430	V
BV _{CES}	Collector to Emitter Breakdown Voltage	$I_{CE} = 10 \text{ mA}, V_{G}$ $R_{GE} = 0, T_{J} = -4$		390	420	450	V
BV _{ECS}	Emitter to Collector Breakdown Voltage	$I_{CE} = -20 \text{ mA}, V_0$ $T_J = 25^{\circ}\text{C}$	_{GE} = 0 V,	28	_	_	V
BV _{GES}	Gate to Emitter Breakdown Voltage	I _{GES} = ±2 mA		±12	±14	-	V
I _{CER}	Collector to Emitter Leakage Current	V _{CE} = 250 V	T _J = 25°C	-	-	25	μΑ
		$R_{GE} = 1 k\Omega$	T _J = 150°C	-	-	1	mA
I _{ECS}	Emitter to Collector Leakage Current	V _{EC} = 24 V	T _J = 25°C	-	-	1	mA
			T _J = 150°C	-	_	40	1
R ₁	Series Gate Resistance		•	-	120	-	Ω
R ₂	Gate to Emitter Resistance			10K	_	30K	Ω
N CHARA	CTERISTICS (Note 5)						
V _{CE(SAT)}	Collector to Emitter Saturation Voltage	I _{CE} = 6 A, V _{GE} =	4 V, T _J = 25°C	_	1.15	1.25	V
V _{CE(SAT)}	Collector to Emitter Saturation Voltage	I _{CE} = 10 A, V _{GE}	= 4.5 V, T _J = 150°C	-	1.35	1.50	V
V _{CE(SAT)}	Collector to Emitter Saturation Voltage	I _{CE} = 15 A, V _{GE}	= 4.5 V, T _J = 150°C	-	1.68	1.85	٧
E _{SCIS}	Self Clamped Inductive Switching	L = 3.0 mHy, RG = 1 K Ω , VGE = 5 V, (Note 1)		-	-	300	mJ
YNAMIC C	HARACTERISTICS	•				•	•
Q _{G(ON)}	Gate Charge	I _{CE} = 10 A, V _{CE}	= 12 V, V _{GE} = 5 V	-	21	-	nC
V _{GE(TH)}	Gate to Emitter Threshold Voltage	I _{CE} = 1 mA	T _J = 25°C	1.3	1.7	2.2	٧
		$V_{CE} = V_{GE}$ $T_{J} = 150^{\circ}C$		0.75	1.2	1.8	
V_{GEP}	Gate to Emitter Plateau Voltage	V _{CE} = 12 V, I _{CE} = 10 A		-	2.8	-	V
WITCHING	CHARACTERISTICS						
td _{(ON)R}	Current Turn-On Delay Time-Resistive	$V_{CE} = 14 \text{ V}, R_{L} = 1 \Omega, V_{GE} = 5 \text{ V},$ $R_{G} = 1 \text{ K}\Omega, T_{J} = 25^{\circ}\text{C}$		-	0.9	4	μs
t _{rR}	Current Rise Time-Resistive			-	1.9	7	1
td _{(OFF)L}	Current Turn-Off Delay Time-Inductive	V_{CE} = 300 V, L = 1 mH, V_{GE} = 5 V, R_{G} = 1 K Ω , I_{CE} = 6.5 A, T_{J} = 25°C		-	4.8	15	
t _{fL}	Current Fall Time-Inductive			-	2.0	15	1

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

PACKAGE MARKING AND DEVICE ORDERING INFORMATION

D	evice Marking	Device	Package	Reel Diameter	Tape Width	Qty [†]
FG	D3040G2	FGD3040G2-F085V	DPAK (Pb-Free)	330 mm	16 mm	2500

[†]For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

TYPICAL CHARACTERISTICS

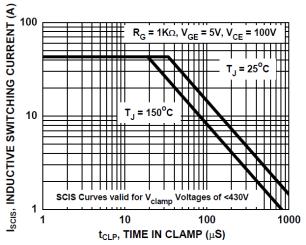


Figure 1. Self Clamped Inductive Switching Current vs. Time in Clamp

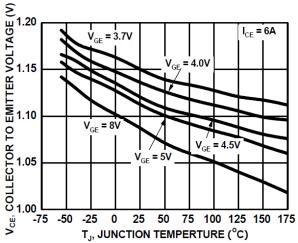


Figure 3. Collector to Emitter On-State Voltage vs. Junction Temperature

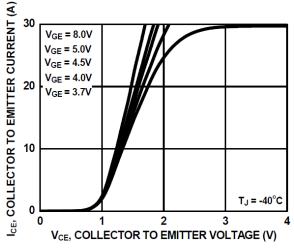


Figure 5. Collector to Emitter On-State Voltage vs. Collector Current

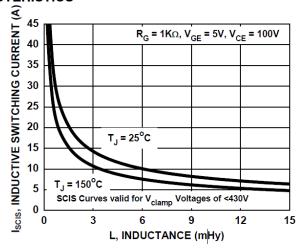


Figure 2. Self Clamped Inductive Switching Current vs. Inductance

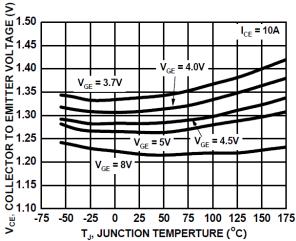


Figure 4. Collector to Emitter On-State Voltage vs. Junction Temperature

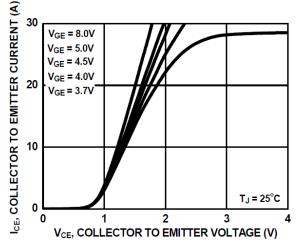


Figure 6. Collector to Emitter On-State Voltage vs. Collector Current

TYPICAL CHARACTERISTICS (continued)

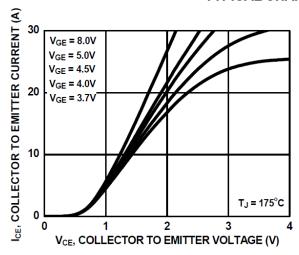


Figure 7. Collector to Emitter On-State Voltage vs.
Collector Current

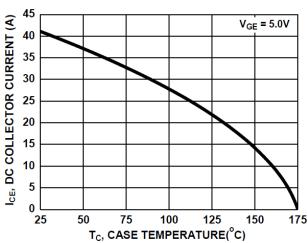


Figure 9. DC Collector Current vs. Case Temperature

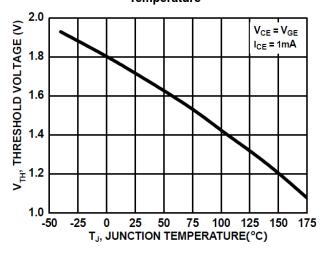


Figure 11. Threshold Voltage vs. Junction Temperature

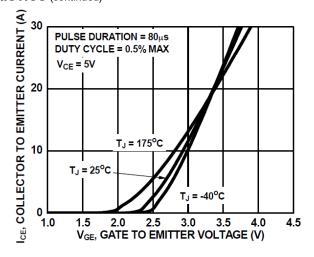


Figure 8. Transfer Characteristics

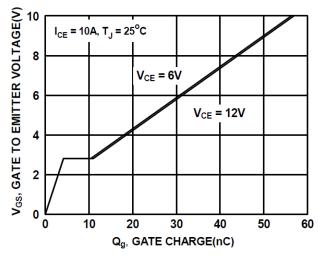


Figure 10. Gate Charge

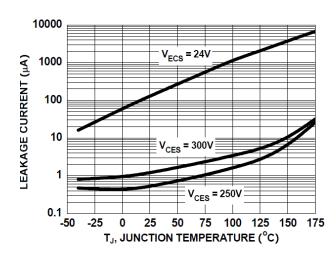
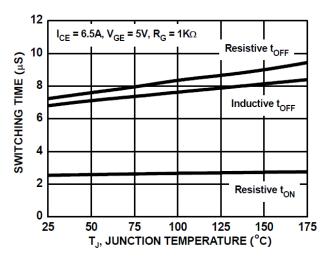


Figure 12. Leakage Current vs. Junction Temperature

TYPICAL CHARACTERISTICS (continued)



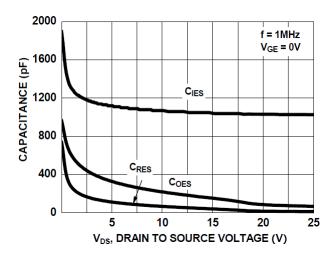


Figure 13. Switching Time vs. Junction Temperature

Figure 14. Capacitance vs. Collector to Emitter Voltage

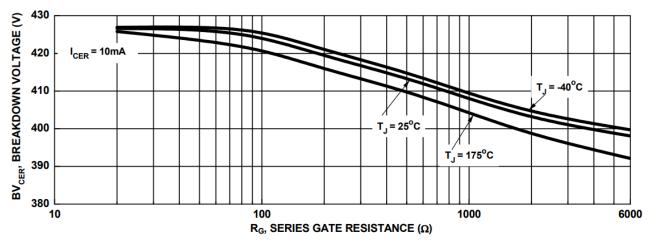


Figure 15. Break down Voltage vs. Series Resistance

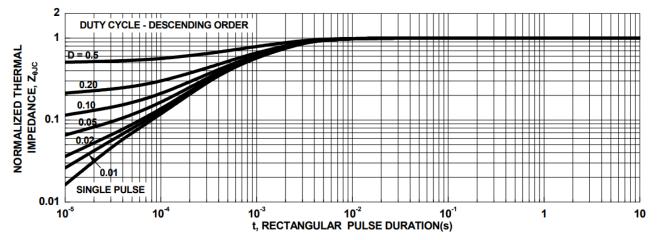


Figure 16. IGBT Normalized Transient Thermal Impedance, Junction to Case

TYPICAL CHARACTERISTICS (continued)

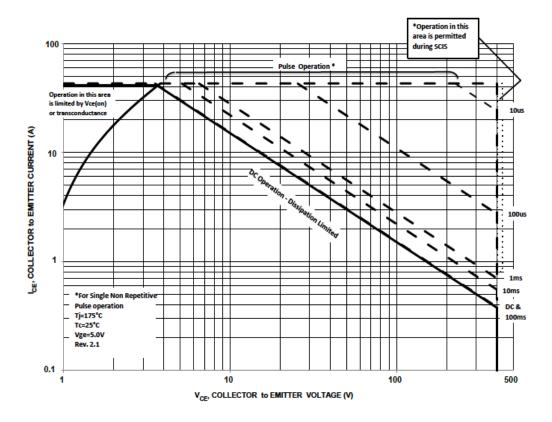


Figure 17. Forward Safe Operating Area

TEST CIRCUIT AND WAVEFORMS

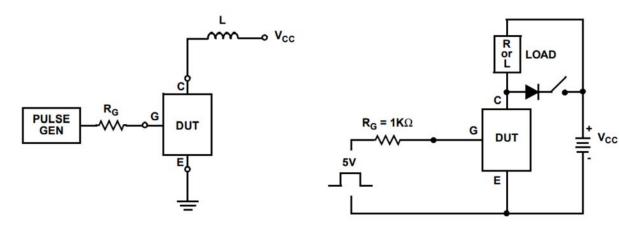


Figure 18. Inductive Switching Test Circuit

Figure 19. $t_{\mbox{\scriptsize ON}}$ and $t_{\mbox{\scriptsize OFF}}$ Switching Test Circuit

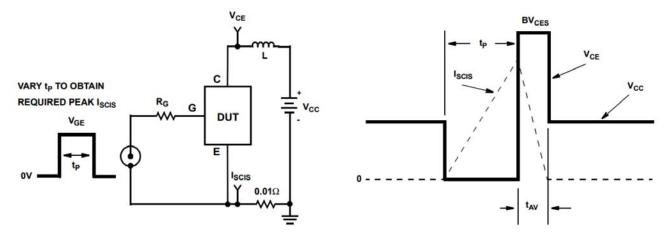


Figure 20. Energy Test Circuit

Figure 21. Energy Waveforms

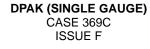
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ROTATED 90° CW

STYLE 1:

STYLE 2:





DATE 21 JUL 2015

- IOTES. 1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994. 2. CONTROLLING DIMENSION: INCHES. 3. THERMAL PAD CONTOUR OPTIONAL WITHIN DI-

- MENSIONS b3, L3 and Z.

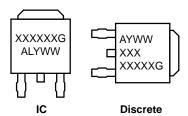
 Jimensions b And E DO NOT INCLUDE MOLD FLASH, PROTRUSIONS, OR BURRS. MOLD FLASH, PROTRUSIONS, OR GATE BURRS SHALL NOT EXCEED 0.006 INCHES PER SIDE.

 MENSIONS D AND E ARE DETERMINED AT THE
- OUTERMOST EXTREMES OF THE PLASTIC BODY.

 6. DATUMS A AND B ARE DETERMINED AT DATUM
- 7. OPTIONAL MOLD FEATURE.

	INCHES MILLIMETERS		IETERS	
DIM	MIN	MAX	MIN	MAX
Α	0.086	0.094	2.18	2.38
A1	0.000	0.005	0.00	0.13
b	0.025	0.035	0.63	0.89
b2	0.028	0.045	0.72	1.14
b3	0.180	0.215	4.57	5.46
С	0.018	0.024	0.46	0.61
c2	0.018	0.024	0.46	0.61
D	0.235	0.245	5.97	6.22
E	0.250	0.265	6.35	6.73
е	0.090	BSC	2.29	BSC
Н	0.370	0.410	9.40	10.41
L	0.055	0.070	1.40	1.78
L1	0.114 REF		2.90 REF	
L2	0.020	BSC	0.51	BSC
L3	0.035	0.050	0.89	1.27
L4		0.040		1.01
Z	0.155		3.93	

GENERIC MARKING DIAGRAM*



XXXXXX = Device Code = Assembly Location Α = Wafer Lot L

Υ = Year WW = Work Week G = Pb-Free Package

*This information is generic. Please refer to device data sheet for actual part marking.

В L3 Ζ Ո DETAIL A NOTE 7 **BOTTOM VIEW** Cb2 е SIDE VIEW | \oplus | 0.005 (0.13) lacktriangle C **TOP VIEW** Z Ħ L2 GAUGE C SEATING PLANE **BOTTOM VIEW** Α1 ALTERNATE CONSTRUCTIONS **DETAIL A**

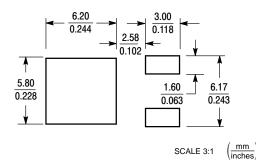
3. EMITTER	3. SOURCE	 ANODE CATHODE 	3. GATE	3. CATHODE
4. COLLECTOR	4. DRAIN		4. ANODE	4. ANODE
3. GATE 3. EMI	LECTOR 2. TTER 3.	N/C PIN CATHODE ANODE	E 9: 1. ANODE 2. CATHODE 3. RESISTOR ADJUST 4. CATHODE	STYLE 10: PIN 1. CATHODE 2. ANODE 3. CATHODE 4. ANODE

STYLE 4:

STYLE 5:

STYLE 3:

SOLDERING FOOTPRINT*



*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

DESCRIPTION:	DPAK SINGLE GAUGE SURFACE MOU	NT	PAGE 1 OF 2
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STATUS:	ON SEMICONDUCTOR STANDARD		
DOCUMENT NUMBER:	98AON10527D	Electronic versions are uncontrolle	'



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98AON10527	7D

PAGE 2 OF 2

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ISSUE	REVISION	DATE
0	RELEASED FOR PRODUCTION. REQ. BY L. GAN	24 SEP 2001
Α	ADDED STYLE 8. REQ. BY S. ALLEN.	06 AUG 2008
В	ADDED STYLE 9. REQ. BY D. WARNER.	16 JAN 2009
С	ADDED STYLE 10. REQ. BY S. ALLEN.	09 JUN 2009
D	RELABELED DRAWING TO JEDEC STANDARDS. ADDED SIDE VIEW DETAIL A. CORRECTED MARKING INFORMATION. REQ. BY D. TRUHITTE.	29 JUN 2010
E	ADDED ALTERNATE CONSTRUCTION BOTTOM VIEW. MODIFIED DIMENSIONS b2 AND L1. CORRECTED MARKING DIAGRAM FOR DISCRETE. REQ. BY I. CAMBALIZA.	06 FEB 2014
F	ADDED SECOND ALTERNATE CONSTRUCTION BOTTOM VIEW. REQ. BY K. MUSTAFA.	21 JUL 2015

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